

Notice of References Cited	Application/Control No. 10/728,972	Applicant(s)/Patent Under Reexamination HSIEH, CHIH-WEI	
	Examiner Gail Verbitsky	Art Unit 2859	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0105487	06-2004	Chen, Sanlian	374/163
	B	US-			
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	E	US-			
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FOREIGN PATENT DOCUMENTS

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